


<b>Search Notes</b>  	<b>Application/Control No.</b>  10714654	<b>Applicant(s)/Patent Under Reexamination</b>  TAKEKOSHI ET AL.
	<b>Examiner</b>  RANDOLPH CHU	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	100, 128	6/6/2007	ric
705	2.3	6/6/2007	ric
715	716	3/20/2008	ric
707	2	3/20/2008	ric
382	305	10/23/2008	ric
358	403, 404	10/23/2008	ric

SEARCH NOTES		
Search Notes	Date	Examiner
EAST	6/6/2007	ric
Inventor Name Search	6/6/2007	ric
Consult with Wenpeng Chen	6/6/2007	ric
Updated EAST Search	12/7/2007	ric
Updated EAST Search	3/20/2008	ric
STIC Search	10/23/2008	ric
Updated EAST Search	10/23/2008	ric
Consult with Andy Johns	10/23/2008	ric
Updated EAST Search	4/20/2009	ric
Updated EAST Search	9/7/2009	ric

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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